

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.	: 10/652,323)	I hereby certify that this paper and the documents referred to therein are being
Applicants	: Elqaq et al.)	deposited with the United States Postal
Filed	: August 29, 2003)	Service with sufficient postage, as first
	_)	class mail, in an envelope addressed to:
Title: Method	d of Making an Optical)	Commissioner for Patents, P.O. Box 1450,
Device in Sili	con)	Alexandria, VA 22313-1450
)	
Art Unit	: Not yet assigned)	Dated: November 25, 2003
Examiner	: Not yet assigned)	,
)	1/2000
Atty Docket	: 30320/15128)	MiN I IIII. 21101
Customer No	. : 04743)	10 may 10 racy sea
			Michael Muczyński

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

The publications listed on the enclosed Form PTO-1449 are submitted pursuant to 37 CFR §§ 1.56, 1.97, and 1.98. Copies of the publications are enclosed as necessary.

Respectfully submitted,

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PTO-1449 (Modified)

U.S. Department of Commerce Patent and Trademark Office Atty. Docket No. Serial No. 30320/15128 10/652,323
Applicant

INFORMATION DISCLOSURE STATEMENT

Elqaq et al.

Filing Date

August 29, 2003

U.S. PATENT DOCUMENTS						
*Examiner Initials	Document Number	Issue Date	Name	Class	Subclass	Filing Date if Appropriate
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FOREIGN PATENT DOCUMENTS							
*Examiner Initials	Document Number	Publication Date	Country	Class	Subclass	Translation	
						Yes	No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)			
·	"Amorphous Silicon Waveguides and Light Modulators for Integrated Photonics Realized by Low Temperature Plasma Enhanced Chemical Vapor Deposition," Opt.		
	Lett. vol. 21, no. 24, p. 2002-2004 (1996).		
	B. Jalali et al., "Advances in Silicon-on-Insulator Optoelectronics" IEEE J. Sel. Top. Quantum Elec., vol. 4, no. 6, p. 938-947 (Nov./Dec. 1998).		

Examiner	Date Considered			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not				
in conformance and not considered. Include copy of this form with next communication to applicant.				